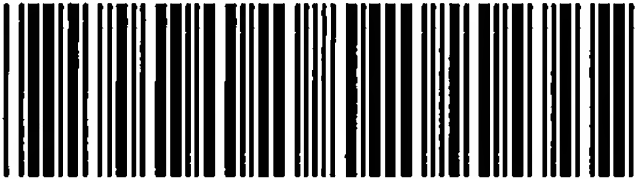


<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>	
	10/634,351	LIN ET AL.	
	<b>Examiner</b>	<b>Art Unit</b>	
	Rip A. Lee	1796	

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524	490	11-10-2007	
524	582	11-10-2007	
524	583	11-10-2007	
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INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	11-10-2007	
EAST/pam updates inventor assignee search	11-10-2007	